

<b>Notice of References Cited</b>	Application/Control No. 10/694,774	Applicant(s)/Patent Under Reexamination HIRANO, YUJI	
	Examiner JYOTHSNA A. VENKAT Ph. D	Art Unit 1615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,800,302	10-2004	Cannell et al.	424/702
	B US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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